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Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

Product Status	Not For New Designs
Core Processor	H85/2000
Core Size	16-Bit
Speed	10MHz
Connectivity	Host Interface (LPC), I <sup>2</sup> C, IrDA, SCI, X-Bus
Peripherals	PWM, WDT
Number of I/O	74
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 3.6V
Data Converters	A/D 8x10b; D/A 2x8b
Oscillator Type	Internal
Operating Temperature	-20°C ~ 75°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/df2140bvte10v

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Item	Page	Revision (See Manual for Details)
Item 23.8.1 Program/ Program-Verify Figure 23.11 Program/Program- Verify Flowchart	Page 625	<section-header><section-header><section-header></section-header></section-header></section-header>
		<ul> <li>2. Verify data is radie 116 bit (evol) with.</li> <li>3. Evol bits for which programming has been completed will be subjected to programming conce again if the result of the subsequent verify operation is N.</li> <li>4. 128-byte ansis for which programming has been completed will be subjected to programming conce again if the result of the subsequent verify operation is N.</li> <li>4. 128-byte ansis for which programming has a completed will be subjected to programming conce again if the result of the subsequent verify operation is N.</li> <li>4. 128-byte ansis for which programming data is expected. The programming concerns again if the result of the subsequent verify operation is N.</li> <li>5. The value of 11 si or 21 as programming data is expected. The programming concerns again if the result of the verify public should be regramming to the subsequent verify operation in the verify public should be regramming to a 22.3, Fash Memory Duancemanics.</li> <li>7. The value Verify Data (Forger program Data (Commonits))</li> <li>7. The operation of the completed regramming completed regramming completed regramming to the scenario of the result of the rescent of the rescent of the result of the result of t</li></ul>
		Section of "Masked ROM" deleted
Section 24 Clock Pulse Generator Figure 24.1 Block Diagram of Clock Pulse Generator	633	Figure 24.1 amended (Before) $\phi$ 2 to f32 $\rightarrow$ (After) $\phi$ 2 to o32
24.5 Subclock Input Circuit	639	Description of "When Subclock Is Not Needed" and "Note on Subclock Usage" added
25.1.1 Standby Control Register (SBYCR)	643	Table amended SCK2 to SCK0 must be cleared to B'000.



Figure 7.1 Block Diagram of DTC



#### 7.2.8 DTC Vector Register (DTVECR)

DTVECR enables or disables DTC activation by software, and sets a vector number for the software activation interrupt.

DTVECR is initialized to H'00 at a reset and in hardware standby mode.	
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Bit	Bit Name	Initial Value	R/W	Description
7	SWDTE	0	R/W	DTC Software Activation Enable
				Setting this bit to 1 activates DTC. Only 1 can always be written to this bit. 0 can be written to after reading 1 from this bit.
				[Clearing conditions]
				• When the DISEL bit is 0 and the specified number of transfers have not ended.
				<ul> <li>When 0 is written to the DISEL bit after a software- activated data transfer end interrupt (SWDTEND) request has been sent to the CPU.</li> </ul>
				[Holding conditions]
				When the DISEL bit is 1 and data transfer has ended
				• When the specified number of transfers have ended.
				During data transfer activated by software
6	DTVEC6	0	R/W	DTC Software Activation Vectors 6 to 0
5	DTVEC5	0	R/W	These bits specify a vector number for DTC software
4	DTVEC4	0	R/W	activation.
3	DTVEC3	0	R/W	The vector address is expressed as H'0400 + (vector
2	DTVEC2	0	R/W	H'10, the vector address is H'0420. When the SWDTE
1	DTVEC1	0	R/W	bit is 0, these bits can be written to.
0	DTVEC0	0	R/W	

#### • P66/FTOB/CIN6/KIN6/IRQ6

The pin function is switched as shown below according to the combination of the OEB bit in TOCR of the FRT and the P66DDR bit.

OEB	0		1
P66DDR	0	1	_
Pin Function	P66 input pin	P66 output pin	FTOB output pin
	$\overline{IRQ6}$ input pin, $\overline{KIN6}$ input pin, CIN6 input pin*		

Note: \* This pin is used as the IRQ6 input pin when bit IRQ6E is set to 1 in IER while the KMIMR6 bit in KMIMR is 0. It can always be used as the KIN6 or CIN6 input pin.

#### • P65/FTID/CIN5/KIN5

0	1		
P65 input pin	P65 output pin		
FTID input pin, $\overline{KIN5}$ input pin, CIN5 input pin*			
	P65 input pin FTID input pin, KIN5 in		

Note: \* This pin can always be used as the FTID, KIN5, or CIN5 input pin.

#### • P64/FTIC/CIN4/KIN4/CLAMPO

The pin function is switched as shown below according to the combination of the CLOE bit in TCONRO of the timer connection function and the P64DDR bit.

CLOE	(	1	
P64DDR	0	1	—
Pin Function	P64 input pin	P64 output pin	CLAMPO output pin
	FTIC input pin, KIN4 input pin, CIN4 input pin*		

Note: \* This pin can always be used as the FTIC, KIN4, or CIN4 input pin.

#### • P63/FTIB/CIN3/KIN3/VFBACKI

P63DDR	0	1
Pin Function	P63 input pin	P63 output pin
	FTIB input pin, VFBACKI input pi	n, $\overline{\text{KIN3}}$ input pin, CIN3 input pin <sup>*</sup>

Note: \* This pin can always be used as the FTIB, KIN3, CIN3, or VFBACKI input pin.

#### • P62/FTIA/CIN2/KIN2/VSYNCI/TMIY

P62DDR	0	1
Pin Function	P62 input pin	P62 output pin
	FTIA input pin, VSYNCI input pir CIN2 in	n, TMIY input pin, KIN2 input pin, put pin*

Note: \* This pin can always be used as the FTIA, TMIY, KIN2, CIN2, or VSYNCI input pin.

### • P61/FTOA/CIN1/KIN1/VSYNCO

The pin function is switched as shown below according to the combination of the OEA bit in TOCR of the FRT, the VOE bit in TCONRO of the timer connection function, and the P61DDR bit.

VOE		1		
OEA	(	)	1	—
P61DDR	0	1	—	_
Pin Function	P61 input pin P61 output pin		FTOA output pin	VSYNCO output pin
	KIN1 input pin, CIN1 input pin*			

Note: \* When this pin is used as the VSYNCO pin, bit OEA in TOCR of the FRT must be cleared to 0. This pin can always be used as the KIN1 or CIN1 input pin.

#### • P60/FTCI/CIN0/KIN0/HFBACKI/TMIX

P60DDR	0	1
Pin Function	P60 input pin	P60 output pin
	FTCI input pin, HFBACKI input pi CIN0 in	in, TMIX input pin, KIN0 input pin, put pin*

Note: \* This pin is used as the FTCI input pin when an external clock is selected with bits CKS1 and CKS0 in TCR of the FRT. It can always be used as the TMIX, KINO, CINO, or HFBACKI input pin.



### 8.15.4 Port E and Port F Nch-OD Control Register (PENOCR, PFNOCR)

PENOCR and PFNOCR specify the output driver type for pins on ports E and F which are configured as outputs on a bit-by-bit basis.

Bit	Bit Name	Initial Value	R/W	Description
7	PE7NOCR	0	R/W	0: CMOS (p-channel driver enabled)
6	PE6NOCR	0	R/W	1: N-channel open drain (p-channel driver
5	PE5NOCR	0	R/W	disabled)
4	PE4NOCR	0	R/W	
3	PE3NOCR	0	R/W	_
2	PE2NOCR	0	R/W	_
1	PE1NOCR	0	R/W	_
0	PE0NOCR	0	R/W	_

Bit	Bit Name	Initial Value	R/W	Description
7	PF7NOCR	0	R/W	0: CMOS (p-channel driver enabled)
6	PF6NOCR	0	R/W	1: N-channel open drain (p-channel driver
5	PF5NOCR	0	R/W	- disabled)
4	PF4NOCR	0	R/W	-
3	PF3NOCR	0	R/W	-
2	PF2NOCR	0	R/W	-
1	PF1NOCR	0	R/W	-
0	PF0NOCR	0	R/W	-

#### 8.15.5 Pin Functions

DDR	(	)	1				
NOCR	-	_	(	)	1		
ODR	0 1		0	1	0	1	
N-ch. driver	O	FF	ON	N OFF ON OF			
P-ch. driver	O	FF	OFF	ON	0	FF	
Input pull-up MOS	OFF	ON	OFF				
Pin function	Inpu	ıt pin	Output pin				

### 9.4 Operation

The upper four bits of PWDR specify the duty cycle of the basic pulse as 0/16 to 15/16 with a resolution of 1/16. Table 9.4 shows the duty cycles of the basic pulse.

Upper 4 Bits	Basic Pulse Waveform (Internal)
0000	0 1 2 3 4 5 6 7 8 9 A B C D E F 0
0001	ΓΙ
0010	
0011	
0100	
0101	
0110	
0111	
1000	
1001	
1010	
1011	
1100	
1101	
1110	
1111	

Table 9.4Duty Cycle of Basic Pulse

The lower four bits of PWDR specify the position of pulses added to the 16 basic pulses. An additional pulse adds a high period (when OS = 0) with a width equal to the resolution before the rising edge of a basic pulse. When the upper four bits of PWDR are 0000, there is no rising edge of the basic pulse, but the timing for adding pulses is the same. Table 9.5 shows the positions of

### 9.5 Usage Note

### 9.5.1 Module Stop Mode Setting

PWM operation can be enabled or disabled using the module stop control register. The initial setting is for PWM operation to be halted. Register access is enabled by canceling the module stop mode. For details, refer to section 26, Power-Down Modes.





Figure 11.12 Timing of Output Compare Flag (OCFA or OCFB) Setting

#### 11.5.8 Timing of FRC Overflow Flag Setting

The FRC overflow flag (OVF) is set to 1 when FRC overflows (changes from H'FFFF to H'0000). Figure 11.13 shows the timing of setting the OVF flag.



Figure 11.13 Timing of Overflow Flag (OVF) Setting

Figure 16.1 shows a block diagram of the  $I^2C$  bus interface. Figure 16.2 shows an example of I/O pin connections to external circuits. Since  $I^2C$  bus interface I/O pins are different in structure from normal port pins, they have different specifications for permissible applied voltages. For details, see section 28, Electrical Characteristics.



Figure 16.1 Block Diagram of I<sup>2</sup>C Bus Interface

transfer using the DTC. The ICDRE or ICDRF flag is cleared, however, since the specified number of ICDR reads or writes have been completed.

Tables 16.4 and 16.5 show the relationship between the flags and the transfer states.

MST	TRS	BBSY	ESTP	STOP	IRTR	AASX	AL	AAS	ADZ	ACKB	ICDRF	ICDRE	State
1	1	0	0	0	0	0↓	0	0↓	0↓	0	_	0	Idle state (flag clearing required)
1	1	1↑	0	0	1↑	0	0	0	0	0	—	1↑	Start condition detected
1	_	1	0	0	—	0	0	0	0	_	—	—	Wait state
1	1	1	0	0	_	0	0	0	0	1↑	_	_	Transmission end (ACKE=1 and ACKB=1)
1	1	1	0	0	1↑	0	0	0	0	0	_	1↑	Transmission end with ICDRE=0
1	1	1	0	0	_	0	0	0	0	0	_	0↓	ICDR write with the above state
1	1	1	0	0	_	0	0	0	0	0	_	1	Transmission end with ICDRE=1
1	1	1	0	0	_	0	0	0	0	0	_	0↓	ICDR write with the above state or after start condition detected
1	1	1	0	0	1↑	0	0	0	0	0	_	1↑	Automatic data transfer from ICDRT to ICDRS with the above state
1	0	1	0	0	1↑	0	0	0	0	_	1↑	_	Reception end with ICDRF=0
1	0	1	0	0	_	0	0	0	0	_	0↓	_	ICDR read with the above state
1	0	1	0	0	_	0	0	0	0	_	1	_	Reception end with ICDRF=1
1	0	1	0	0	_	0	0	0	0	_	0↓	_	ICDR read with the above state
1	0	1	0	0	1↑	0	0	0	0	_	1↑	_	Automatic data transfer from ICDRS to ICDRR with the above state
0↓	0↓	1	0	0	_	0	1↑	0	0	_	—	_	Arbitration lost
1	_	0↓	0	0	_	0	0	0	0	_	_	0↓	Stop condition detected

#### Table 16.4 Flags and Transfer States (Master Mode)

Legend:

0: 0-state retained

1: 1-state retained

-: Previous state retained

 $0\downarrow$ : Cleared to 0

11: Set to 1

#### 16.4.6 Slave Transmit Operation

If the slave address matches to the address in the first frame (address reception frame) following the start condition detection when the 8th bit data  $(R/\overline{W})$  is 1 (read), the TRS bit in ICCR is automatically set to 1 and the mode changes to slave transmit mode.

Figure 16.24 shows the sample flowchart for the operations in slave transmit mode.



Figure 16.24 Sample Flowchart for Slave Transmit Mode

Section 19	Host Interface LPC Interface (	LPC)
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			R	w	
Bit	Bit Name	Initial Value	Slave	Host	Description
6	CLKREQ	0	R	_	LCLK Request
					Indicates that the host interface's SERIRQ output is requesting a restart of LCLK.
					0: No LCLK restart request
					[Clearing conditions]
					LPC hardware reset or LPC software reset
					LPC hardware shutdown or LPC software shutdown
					SERIRQ is set to continuous mode
					• There are no further interrupts for transfer to the host in quiet mode
					1: LCLK restart request issued
					[Setting condition]
					In quiet mode, SERIRQ interrupt output becomes necessary while LCLK is stopped
5	IRQBSY	0	R	_	SERIRQ Busy
					Indicates that the host interface's SERIRQ signal is engaged in transfer processing.
					0: SERIRQ transfer frame wait state
					[Clearing conditions]
					LPC hardware reset or LPC software reset
					LPC hardware shutdown or LPC software shutdown
					End of SERIRQ transfer frame
					1: SERIRQ transfer processing in progress
					[Setting condition]
					Start of SERIRQ transfer frame



## Section 23 ROM

This LSI has an on-chip flash memory. The features of the flash memory are summarized below.

A block diagram of the flash memory is shown in figure 23.1.

### 23.1 Features

• Size

Product Classification	RAM Capacitance	RAM Address
H8S/2161B	128 kbytes	H'000000–H'01FFFF (mode 2) H'0000–H'DFFF (mode 3)
H8S/2160B	64 kbytes	H'000000–H'00FFFF (mode 2) H'0000–H'DFFF (mode 3)
H8S/2141B	128 kbytes	H'000000–H'01FFFF (mode 2) H'0000–H'DFFF (mode 3)
H8S/2140B	64 kbytes	H'000000–H'00FFFF (mode 2) H'0000–H'DFFF (mode 3)
H8S/2145B	256 kbytes	H'000000–H'03FFFF (mode 2) H'0000–H'DFFF (mode 3)
H8S/2148B	128 kbytes	H'000000–H'01FFFF (mode 2) H'0000–H'DFFF (mode 3)

• Programming/erase methods

The flash memory is programmed 128 bytes at a time. Erase is performed in single-block units. The flash memory is configured as follows:

- 64-kbyte version: 8 kbytes  $\times$  2 blocks, 16 kbytes  $\times$  1 block, 28 kbytes  $\times$  1 block, and 1 kbyte  $\times$  4 blocks
- 128-kbyte version: 32 kbytes × 2 blocks, 8 kbytes × 2 blocks, 16 kbytes × 1 block, 28 kbytes × 1 block, and 1 kbyte × 4 blocks
- 256-kbyte version: 64 kbytes  $\times$  3 blocks, 32 kbytes  $\times$  1 block, and 4 kbytes  $\times$  8 blocks.

To erase the entire flash memory, each block must be erased in turn.

• Programming/erase time

It takes 10 ms (typ.) to program the flash memory 128 bytes at a time; 80  $\mu$ s (typ.) per 1 byte. Erasing one block takes 100 ms (typ.).

#### 23.5.2 Flash Memory Control Register 2 (FLMCR2)

FLMCR2 monitors the state of flash memory programming/erasing protection (error protection) and sets up the flash memory to transit to programming/erasing mode. FLMCR2 is initialized to H'00 by a reset or in hardware standby mode. The ESU and PSU bits are cleared to 0 in software standby mode, sub-active mode, sub-sleep mode, or watch mode, or when the SWE bit in FLMCR1 is cleared to 0.

Bit	Bit Name	Initial Value	R/W	Description
7	FLER	0	R	Flash memory error
				Indicates that an error has occurred during flash memory programming/erasing. When this bit is set to 1, flash memory goes to the error-protection state.
				For details, see section 23.9.3, Error Protection.
6 to 2	_	All 0	R/(W)	Reserved
				The initial values should not be modified.
1	ESU	0	R/W	Erase Setup
				When this bit is set to 1 while $SWE = 1$ , the flash memory transits to the erase setup state. When it is cleared to 0, the erase setup state is cancelled. Set this bit to 1 before setting the E bit in FLMCR1 to 1.
0	PSU	0	R/W	Program Setup
_				When this bit is set to 1 while SWE = 1, the flash memory transits to the program setup state. When it is cleared to 0, the program setup state is cancelled. Set this bit to 1 before setting the P bit in FLMCR1 to 1.

#### Table 27.7 Bus Timing (2) (Advanced Mode)

Conditions:  $V_{cc} = 2.7 \text{ V}$  to 3.6 V,  $V_{cc}B = 2.7 \text{ V}$  to 5.5 V,  $V_{ss} = 0 \text{ V}$ ,  $\phi = 2 \text{ MHz}$  to maximum operating frequency,  $T_a = -20$  to  $+75^{\circ}C$ 

	Con	dition	_			
		10 MHz		_	Test	
Item	Symbol	Min	Max	Unit	Conditions	
Address delay time	t <sub>AD</sub>	_	60	ns	Figures 27.11	
Address setup time	t <sub>AS</sub>	$0.5 imes t_{_{cyc}}-30$	_	ns	to 27.15	
Address hold time	t <sub>AH</sub>	$0.5 imes t_{_{cyc}}-20$	_	ns		
$\overline{\text{CS}}$ delay time ( $\overline{\text{IOS}}$ )	t <sub>csd</sub>	_	60	ns		
AS delay time	t <sub>ASD</sub>	—	60	ns		
RD delay time 1	t <sub>RSD1</sub>	—	60	ns		
RD delay time 2	t <sub>RSD2</sub>	—	60	ns		
Read data setup time	t <sub>RDS</sub>	35	—	ns	-	
Read data hold time	t <sub>RDH</sub>	0	_	ns	-	
Read data access time 1	t <sub>ACC1</sub>	_	$1.0  imes t_{_{cyc}} - 80$	ns	-	
Read data access time 2	t <sub>ACC2</sub>	_	$1.5  imes t_{_{cyc}} - 50$	ns		
Read data access time 3	t <sub>ACC3</sub>	—	$2.0  imes t_{_{cyc}} - 80$	ns	-	
Read data access time 4	t <sub>ACC4</sub>	_	$2.5 imes t_{_{cyc}}-50$	ns	-	
Read data access time 5	t <sub>ACC5</sub>	—	$3.0  imes t_{_{ m cyc}} - 80$	ns	-	
HWR, LWR delay time 1	$\mathbf{t}_{_{\mathrm{WRD1}}}$	_	60	ns	-	
HWR, LWR delay time 2	$\mathbf{t}_{_{\mathrm{WRD2}}}$	_	60	ns		
HWR, LWR pulse width 1	t <sub>wsw1</sub>	$1.0  imes t_{_{cyc}} - 40$	—	ns	-	
HWR, LWR pulse width 2	t <sub>wsw2</sub>	$1.5  imes t_{_{cyc}} - 40$	_	ns	-	
Write data delay time	t <sub>wdd</sub>	_	60	ns	-	
Write data setup time	t <sub>wds</sub>	0	—	ns	-	
Write data hold time	$\mathbf{t}_{WDH}$	20	_	ns	-	
WAIT setup time	t <sub>wrs</sub>	60	_	ns	-	
WAIT hold time	t <sub>wth</sub>	10	_	ns		

#### Table 27.17 DC Characteristics (4)

Conditions:  $V_{cc} = 4.0 \text{ V}$  to 5.5 V,  $V_{cc}B = 4.0 \text{ V}$  to 5.5 V,  $AV_{cc}^{*1} = 4.0 \text{ V}$  to 5.5 V,  $AV_{ref}^{*1} = 4.0 \text{ V}$  to  $AV_{cc}$ ,  $V_{ss} = AV_{ss}^{*1} = 0 \text{ V}$ ,  $T_a = -20 \text{ to } +75^{\circ}\text{C}$  (normal specification product),  $T_a = -40 \text{ to } +85^{\circ}\text{C}$  (wide range temperature specification product)

	ltem		Symbol	Min	Тур	Max	Unit	Test Conditions
Input	RES	I <sub>.in</sub>			10.0	μA	$V_{in} = 0.5 \text{ to}$	
leakage current	STBY, NMI, MD1 MD0	_	_	_	1.0		$V_{cc} - 0.5 V$	
	Port 7		_	_	_	1.0		$V_{in}$ = 0.5 to AV <sub>cc</sub> - 0.5 V
Three-state leakage current (off state)	Ports 1 to 6, 8, 9, A <sup>*4</sup> , B		I <sub>tsi</sub>	_	_	1.0	μA	$\begin{array}{l} V_{_{in}}=0.5 \ to \\ V_{_{CC}}-0.5 \ V, \\ V_{_{in}}=0.5 \ to \\ V_{_{CC}}B-0.5 \ V \end{array}$
Input pull-up	Ports 1 to 3		$-I_{P}$	30		300	μA	$V_{in} = 0 V,$
MOS current	Ports A <sup>*4</sup> , B, 6 (P6PUE = 0)	_	60	_	600		$V_{cc} = 4.5 V$ to 5.5 V, $V_{cc}B = 4.5 V$ to 5.5 V	
	Port 6 (P6PUE = 1)	-	15	—	200			
	Ports 1 to 3	—	20	_	200	μA	$V_{in} = 0 V,$ $V_{cc} = 4.0 V$ to 4.5 V, $V_{cc} = 4.0 V$	
	Ports A <sup>*4</sup> , B, 6 (P6PUE = 0)	_	40	—	500			
	Port 6 (P6PUE = 1)		-	10	—	150		to 4.5 V
Input	RES	(4)	C <sub>in</sub>	—	_	80	pF	$V_{in} = 0 V,$
capacitance	NMI			_	_	50		f = 1 MHz, T = 25°C
	P52, P97, P42, P86, PA7 to PA2		_	—	20		$T_{a} = 25 \text{ C}$	
	Input pins except (4) above		_	_	—	15		
Current	Normal operation	I <sub>cc</sub>	_	45	58	mA	f = 16 MHz	
dissipation*2	Sleep mode		_	_	30	46	mA	f = 16 MHz
	Standby mode <sup>*3</sup>		_	_	1.0	5.0	μA	$T_a \le 50^{\circ}C$
					20.0		50°C < T <sub>a</sub>	

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# Table 27.28 A/D Conversion Characteristics (CIN15 to CIN0 Input: 134/266-State Conversion)

Condition A:	$V_{cc} = 5.0 \text{ V} \pm 10\%, \text{ AV}_{cc} = 5.0 \text{ V} \pm 10\%, \text{ AV}_{ref} = 4.5 \text{ V} \text{ to } \text{AV}_{cc},$
	$V_{ss} = AV_{ss} = 0$ V, $\phi = 2$ MHz to maximum operating frequency,
	$T_a = -20$ to $+75^{\circ}C$ (normal specification product),
	$T_{2} = -40$ to $+85^{\circ}C$ (wide range temperature specification product)

Condition B:  $V_{cc} = 4.0 \text{ V}$  to 5.5 V,  $AV_{cc} = 4.0 \text{ V}$  to 5.5 V,  $AV_{ref} = 4.0 \text{ V}$  to  $AV_{cc}$ ,  $V_{ss} = AV_{ss} = 0 \text{ V}$ ,  $\phi = 2 \text{ MHz}$  to maximum operating frequency,  $T_a = -20 \text{ to } +75^{\circ}\text{C}$  (normal specification product),  $T_a = -40 \text{ to } +85^{\circ}\text{C}$  (wide range temperature specification product)

Condition C:  $V_{cc} = 3.0 \text{ V}$  to  $3.6 \text{ V}^{*4}$ ,  $AV_{cc} = 3.0 \text{ V}$  to  $3.6 \text{ V}^{*4}$ ,  $AV_{ref} = 3.0 \text{ V}$  to  $AV_{cc}^{*4}$ ,  $V_{cc}B = 3.0 \text{ V}$  to  $5.5 \text{ V}^{*4}$ ,  $V_{ss} = AV_{ss} = 0 \text{ V}$ ,  $\phi = 2 \text{ MHz}$  to maximum operating frequency,  $T_a = -20$  to  $+75^{\circ}\text{C}$ 

	С	onditio	on C	С	onditic	on B	(			
	10 MHz				16 MH	lz				
ltem	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
Resolution	10	10	10	10	10	10	10	10	10	bits
Conversion time*3			13.4	—		8.4	—		6.7	μs
Analog input capacitance	_	_	20	_	_	20	_	_	20	pF
Permissible signal- source impedance	—	_	5	_	_	10 <sup>*1</sup> 5 <sup>*2</sup>	_	_	10 <sup>*1</sup> 5 <sup>*2</sup>	kΩ
Nonlinearity error			±11.0	—		±5.0	—		±5.0	LSB
Offset error		_	±11.5	_	_	±5.5	_	_	±5.5	LSB
Full-scale error		_	±11.5	_	_	±5.5	_	_	±5.5	LSB
Quantization error		_	±0.5	_	_	±0.5	_	_	±0.5	LSB
Absolute accuracy	_	_	±12.0	_	_	±6.0	_	_	±6.0	LSB

Notes: 1. When conversion time  $\geq$  11.17 µs (CKS = 0, or  $\phi \leq$  12 MHz at CKS = 1)

2. When conversion time < 11.17  $\mu$ s ( $\phi$  > 12 MHz at CKS = 1)

3. At the maximum operating frequency in single mode.

4. When using CIN, ensure that V<sub>cc</sub> = 3.0 V to 3.6 V, AV<sub>cc</sub> = 3.0 V to 3.6 V, AV<sub>ref</sub> = 3.0 V to 3.6 V, V<sub>cc</sub>B = 3.0 V to 5.5 V.

#### 27.2.6 Flash Memory Characteristics

Table 27.30 shows the flash memory characteristics.

#### Table 27.30 Flash Memory Characteristics (Operation Range at Programming/Erasing)

5-V version conditions:  $V_{cc} = 4.0 \text{ V}$  to 5.5 V,  $V_{ss} = 0 \text{ V}$ ,  $T_a = -20 \text{ to } +75^{\circ}\text{C}$  (normal specification product),  $T_a = -40 \text{ to } +85^{\circ}\text{C}$  (wide range temperature specification product)

3-V version conditions:  $V_{cc} = 3.0 \text{ V}$  to 3.6 V,  $V_{ss} = 0 \text{ V}$ ,  $T_a = -20 \text{ to } +75^{\circ}\text{C}$ 

Item		Symbol	Min	Тур	Мах	Unit	Test Condition
Programming time <sup>*1*2*4</sup>		t <sub>P</sub>	_	10	200	ms/ 128 bytes	
Erase time <sup>*1*3*6</sup>		t_	_	100	1200	ms/block	
Reprogramming count		N <sub>WEG</sub>		_	100	times	
Programming	Wait time after SWE-bit setting*1	х	1	_		μs	
	Wait time after PSU-bit setting*1	у	50	_		μs	
	Wait time after P-bit setting <sup>*1 *4</sup>	z1	28	30	32	μs	$1 \le n \le 6$
		z2	198	200	202	μs	$7 \le n \le 1000$
		z3	8	10	12	μs	Additional write
	Wait time after P-bit clear*1	α	5	_	_	μs	
	Wait time after PSU-bit clear*1	β	5	_	_	μs	
	Wait time after PV-bit setting*1	γ	4	_	_	μs	
	Wait time after dummy write*1	ε	2	_	_	μs	
	Wait time after PV-bit clear*1	η	2	_	_	μs	
	Wait time after SWE-bit clear*1	θ	100	—		μs	
	Maximum programming count <sup>*1 *4 *5</sup>	Ν	_	—	1000	times	
Erase	Wait time after SWE-bit setting*1	х	1	—		μs	
	Wait time after ESU-bit setting*1	у	100	—		μs	
	Wait time after E-bit setting*1*6	z	10	—	100	ms	
	Wait time after E-bit clear*1	α	10	—	_	μs	
	Wait time after ESU-bit clear*1	β	10	—	_	μs	
	Wait time after EV-bit setting*1	γ	20	—	_	μs	
	Wait time after dummy write*1	ε	2	_	_	μs	
	Wait time after EV-bit clear*1	η	4	_	_	μs	
	Wait time after SWE-bit clear*1	θ	100	_	_	μs	
	Maximum erase count*1 *6 *7	N	_	_	120	times	



Figure 27.8 Oscillation Setting Timing (Exiting Software Standby Mode)

